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# On-The-Fly Sampling for Inelastic Incoherent Thermal Neutron Scattering for Monte Carlo Codes

Camden Blake | Nuclear engineering Program  
Rensselaer Polytechnic Institute (RPI)

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# Team Members and Collaborators

- RPI Team Members
  - Camden Blake (PhD Student)
  - Wei Ji (PI)
  - Yaron Danon (Co-PI)
- Collaborators
  - Forrest Brown (retired) – LANL
  - Robert Little - LANL



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## Acknowledgment

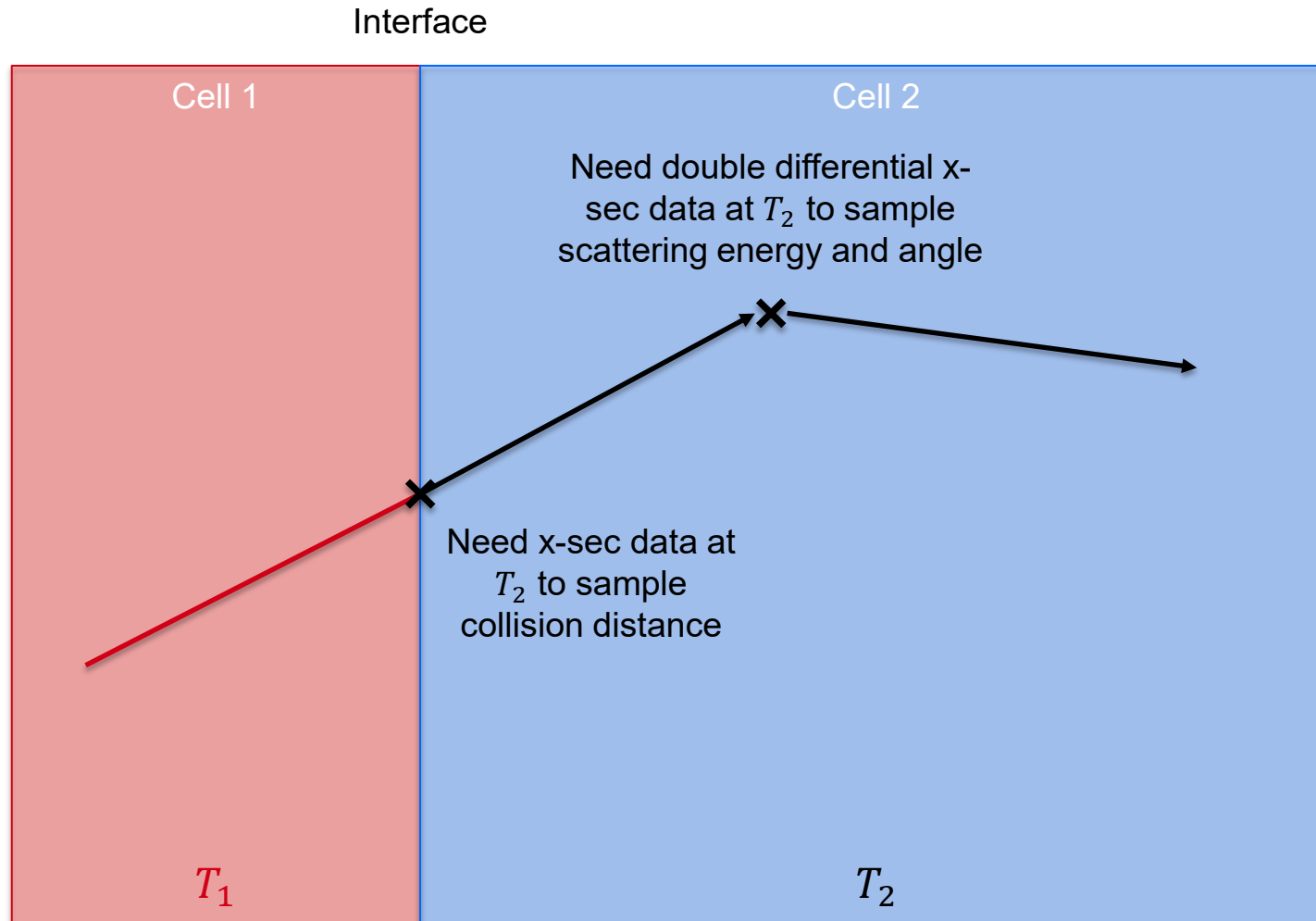
This work was supported by the Nuclear Criticality Safety Program, funded and managed by the National Nuclear Security Administration for the Department of Energy.



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# Project Motivation



$S(\alpha, \beta)$  scattering law  
dominates thermal neutron  
scattering

$$\sigma(E \rightarrow E', \mu, T) = \frac{\sigma_b}{2kT} \sqrt{\frac{E'}{E}} e^{\left(-\frac{\beta}{2}\right)} S(\alpha, \beta, T)$$

$\alpha$ : momentum transfer       $\beta$ : energy transfer

$$\alpha = \frac{E + E' - 2\mu\sqrt{EE'}}{A_0kT} \qquad \beta = \frac{E' - E}{kT}$$

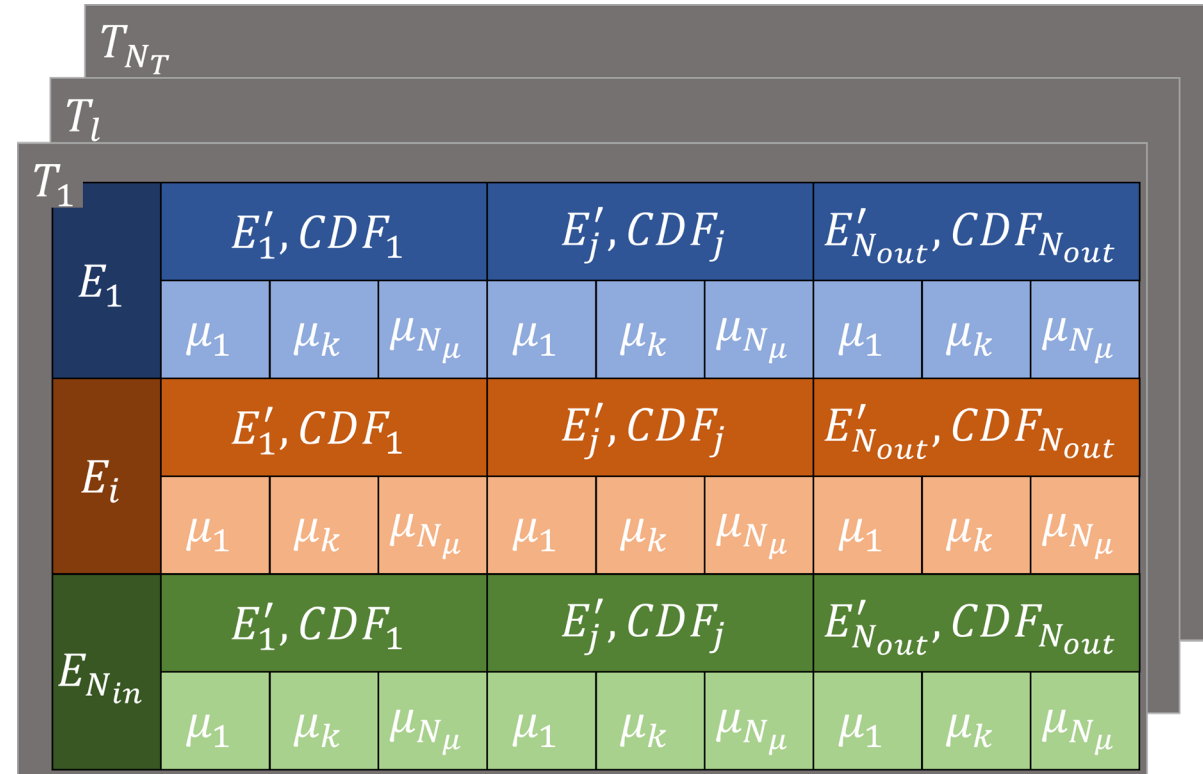
## Project Motivation

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- Current thermal libraries store inelastic incoherent scattering distributions as functions of incident energy, outgoing energy, scattering angle, and temperature  $(E, E', \mu, T)$ .
- Makes MCNP ACE thermal library very large
- Unwieldy for HPC simulations

# Project Motivation

Material	Temperature Range [K]	# Files	Total Size [MB]
be-beo	293.6 - 1200	8	339.34
o-beo	293.6 - 1200	8	280.24
grph	296 - 2000	10	393.99
grph10	296 - 2000	10	328.88
grph30	296 - 2000	10	312.08
h-h2o	283.6 - 800	18	536.1



- ACE Files(ENDF80SaB2): 33 Materials for a total of 9.41 GB

## Project Objective

- Create a method to generate a small thermal library
- Adaptive in temperature
- Retains sampling accuracy
- Minimizes computational burden



**Single file for a material**

**Works for any temperature**

**Only 20-30 MB**

## Approach to Produce the OTF Library

1. Evaluate the Thermal Scattering Law (TSL) for the material of interest  $\rightarrow S(\alpha, \beta, T)$ .
2. Calculate sampling probability distributions (PDFs and CDFs) over the applicable temperature range.
3. Apply a regression model to remove the temperature dependence from the data.



## Approach – Step 1

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- Obtain input leapr data from ENDF/B-VIII.0
- Contains:
  - Material specific model parameters
  - Phonon spectrum
  - Alpha and Beta calculation grids
  - Temperature range for the material

## Approach – Step 1

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- Use leapr to generate ‘high fidelity’  $S(\alpha, \beta, T)$  data
  - Investigating to see if the default alpha and beta grids are enough to linearize sampling distributions
  - A fine temperature grid is chosen, typically using 5K increments

## Approach – Step 2

- Creation of the sampling distributions needed for sampling.

PDFs

$$g(\beta|E, T) = \frac{\exp\left(-\frac{\beta}{2}\right) \int_{\alpha_-}^{\alpha_+} S(\alpha, \beta, T) d\alpha}{\int_{\beta_-}^{\beta_+} \int_{\alpha_-}^{\alpha_+} \exp\left(-\frac{\beta}{2}\right) S(\alpha, \beta, T) d\alpha d\beta}$$



$$\hat{h}(\alpha|\beta, T) = \frac{S(\alpha, \beta, T)}{\int_0^{\infty} S(\alpha, \beta, T) d\alpha}$$

CDFs

$$G(\beta|E, T) = \int_{\beta_-}^{\beta} g(\beta'|E, T) d\beta'$$

$$\hat{H}(\alpha|\beta, T) = \int_0^{\alpha} \hat{h}(\alpha'|\beta, T) d\alpha'$$

## Approach – Step 3

- CDF sampling distributions are fixed to set CDF values and repeated for every temperature.
- $E_i, \beta_j \rightarrow CDF_{i,j}$    $E_i, CDF_j \rightarrow \beta_{i,j}$
- $\beta_i, \alpha_j \rightarrow CDF_{i,j}$    $\beta_i, CDF_j \rightarrow \alpha_{i,j}$
- Polynomial regression is then performed on the  $\beta_{i,j}$  and  $\alpha_{i,j}$  as functions of temperature.

## Approach – Step 3

- This yields a set of coefficients that can be used to recover the alpha and beta value at any temperature OTF.

$T_m$	$\beta_1$	$\beta_j$	$\beta_J$
$E_1$	$CDF_{m,1,1}$	$CDF_{m,1,j}$	$CDF_{m,1,J}$
$E_i$	$CDF_{m,i,1}$	$CDF_{m,i,j}$	$CDF_{m,i,J}$
$E_I$	$CDF_{m,I,1}$	$CDF_{m,I,j}$	$CDF_{m,I,J}$



	$CDF_1$	$CDF_j$	$CDF_J$
$E_1$	$B(T)_{1,1}$	$B(T)_{1,j}$	$B(T)_{1,J}$
$E_i$	$B(T)_{i,1}$	$B(T)_{i,j}$	$B(T)_{i,J}$
$E_I$	$B(T)_{I,1}$	$B(T)_{I,j}$	$B(T)_{I,J}$

## Approach - Result

- Single file for each material
- Small size
- Used for any temperature
- Maintains accuracy
- Not computationally expensive\*

	$CDF_1$		$CDF_j$		$CDF_{N_P}$	
$E_1$	$B_1$	$B_{N_C}$	$B_1$	$B_{N_C}$	$B_1$	$B_{N_C}$
$E_i$	$B_1$	$B_{N_C}$	$B_1$	$B_{N_C}$	$B_1$	$B_{N_C}$
$E_{N_{in}}$	$B_1$	$B_{N_C}$	$B_1$	$B_{N_C}$	$B_1$	$B_{N_C}$

$$\beta = \sum_l^{N_C} B_l * X_\beta(T)$$

	$CDF_1$		$CDF_j$		$CDF_{N_P}$	
$\beta_1$	$A_1$	$A_{N_C}$	$A_1$	$A_{N_C}$	$A_1$	$A_{N_C}$
$\beta_i$	$A_1$	$A_{N_C}$	$A_1$	$A_{N_C}$	$A_1$	$A_{N_C}$
$\beta_{N_F}$	$A_1$	$A_{N_C}$	$A_1$	$A_{N_C}$	$A_1$	$A_{N_C}$

$$\alpha = \sum_l^{N_C} A_l * X_\alpha(T)$$

# Results

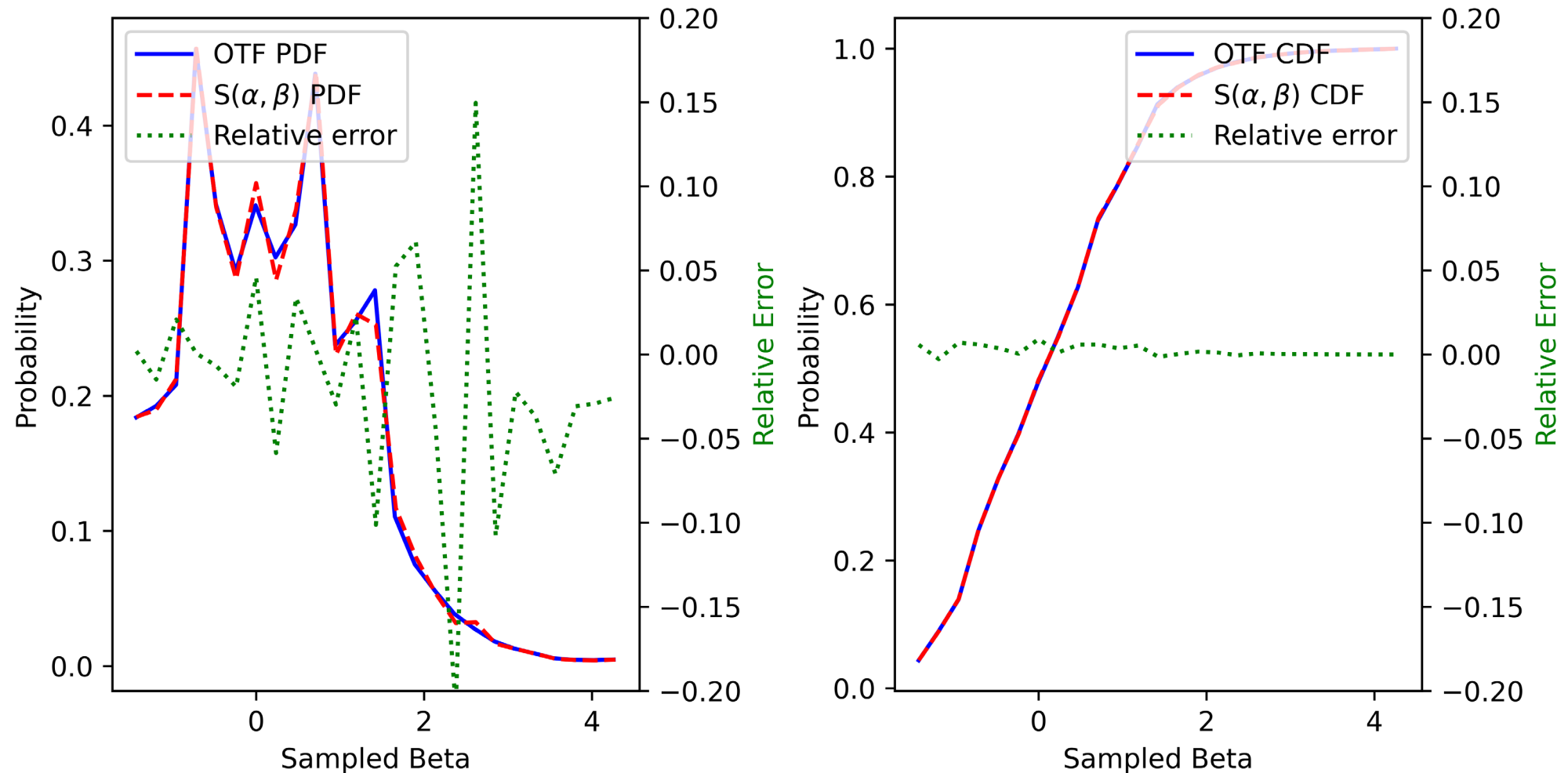
- Currently have 24 materials being treated in this manner
- 9 materials are not being treated
  - Materials with only one temperature:
    - L-CH<sub>4</sub>, S-CH<sub>4</sub>, and HinC5O2H8
  - Materials with problems in leapr input
    - Ortho/Para H and D, SiO<sub>2</sub>-alpha, and SiO<sub>2</sub>-beta

## Results – Small Size

<b>Material</b>	<b>OTF Storage [MB]</b>	<b>Material</b>	<b>OTF Storage [MB]</b>
<b>013-AI-027</b>	5.5	<b>HinIcelh</b>	17.6
<b>026-Fe-056</b>	5.7	<b>OinIcelh</b>	12.6
<b>crystalline-graphite</b>	12.7	<b>OinD2O</b>	12.6
<b>reactor-graphite-10P</b>	12.7	<b>DinD2O</b>	12.6
<b>reactor-graphite-30P</b>	12.7	<b>OinUO2</b>	7.1
<b>Be-metal</b>	7.1	<b>UinUO2</b>	7.1
<b>OinBeO</b>	9.9	<b>NinUN</b>	12.7
<b>BeinBeO</b>	9.9	<b>UinUN</b>	12.7
<b>HinH2O</b>	10.4	<b>HinYH2</b>	12.7
<b>HinCH2</b>	12.7	<b>YinYH2</b>	7.6
<b>CinSiC</b>	9.9	<b>HinZrH</b>	7.1
<b>SiinSiC</b>	9.9	<b>ZrinZrH</b>	4.8

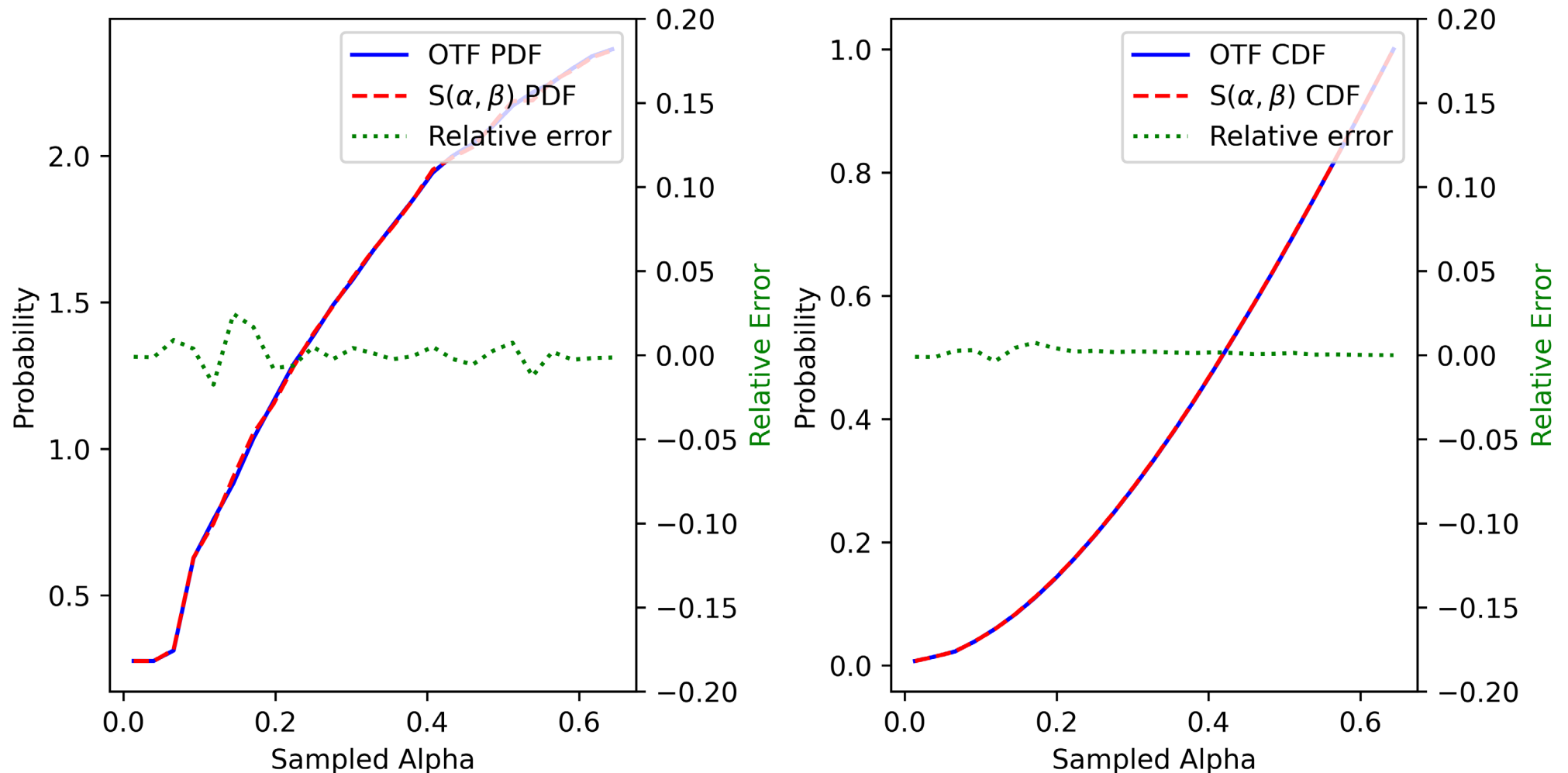


# Results – Maintains Accuracy



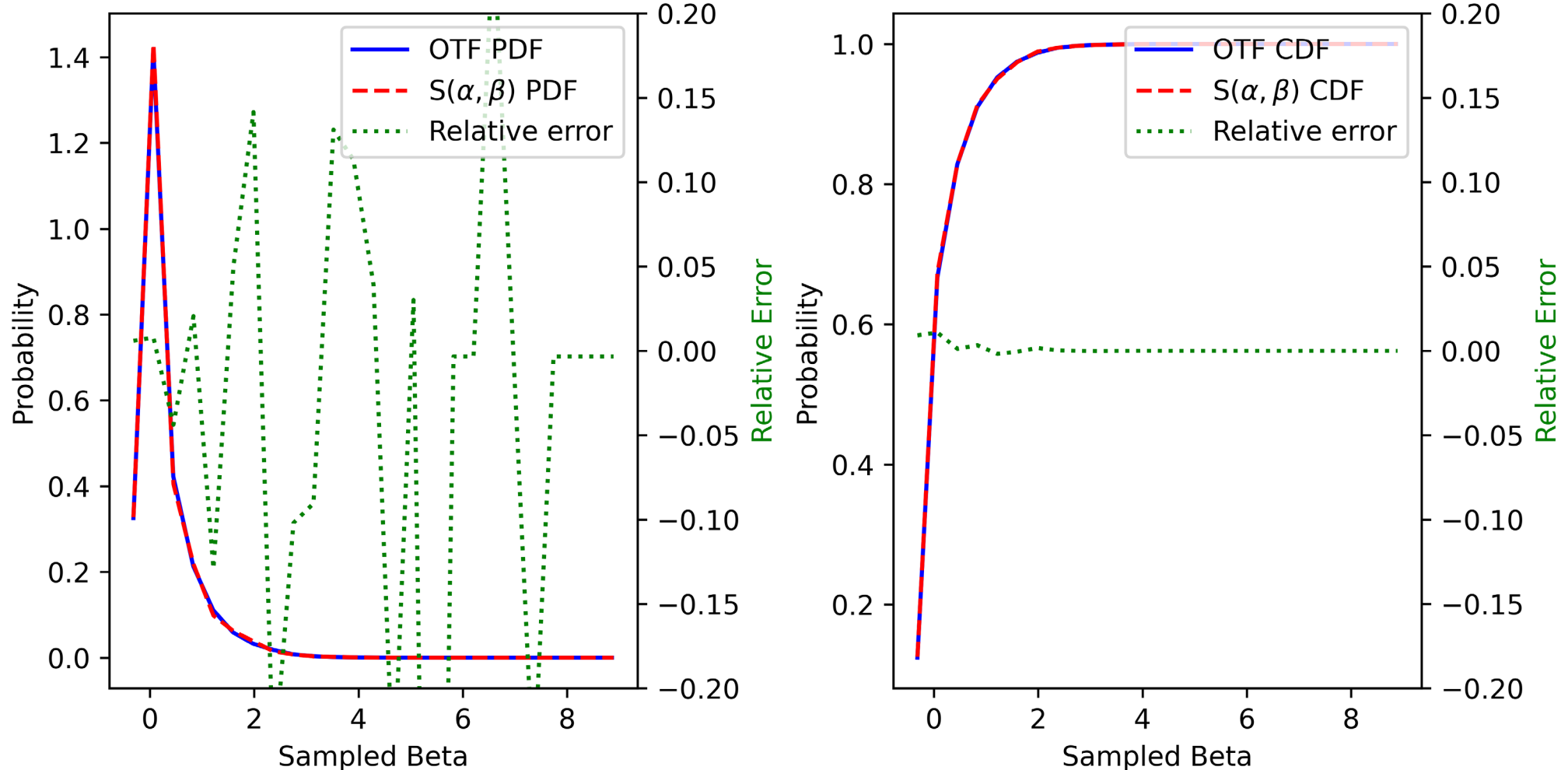
**Sampled  $\beta$  PDF and CDF distributions and associated errors for Be in BeO at 751K and with an incident energy of 0.1 eV.**

# Results – Maintains Accuracy



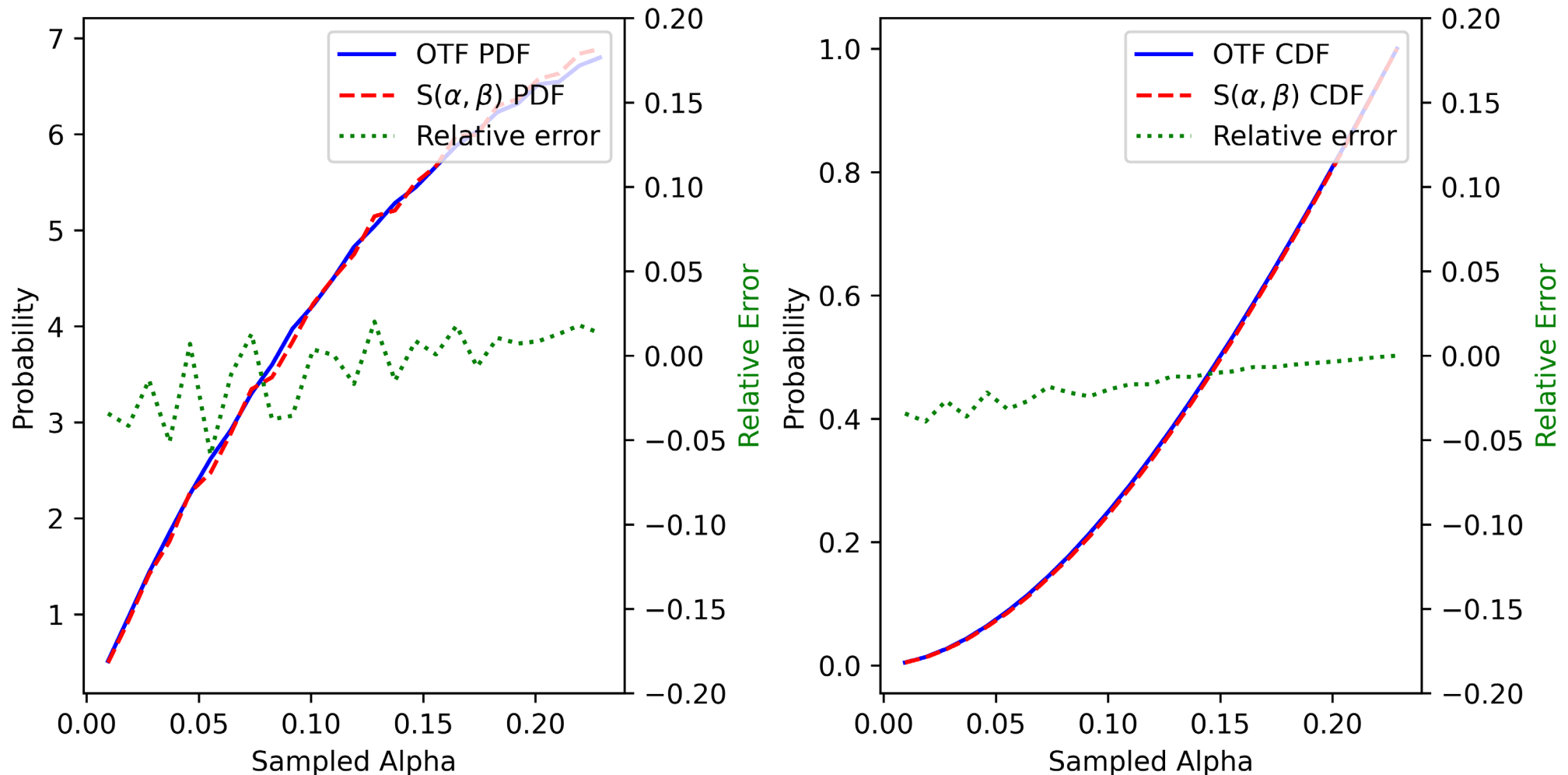
**Sampled  $\alpha$  PDF and CDF distributions and associated errors for Be in BeO at 751K and with an incident energy of 0.1 eV and scattering energy of 0.09 eV.**

# Results – Maintains Accuracy



**Sampled  $\beta$  PDF and CDF distributions and associated errors for graphite at 1146K and with an incident energy of 0.05 eV.**

# Results – Maintains Accuracy



**Sampled  $\alpha$  PDF and CDF distributions and associated errors for graphite at 1146K and with an incident energy of 0.05 eV and scattering energy of 0.09 eV.**

## Results – Sampling Times

Material	$S(\alpha, \beta)$ [s]	OTF [s]	Ratio	Material	$S(\alpha, \beta)$ [s]	OTF [s]	Ratio
013-Al-027	0.119	0.446	3.758	HinIcelh	0.127	0.305	2.403
026-Fe-056	0.114	0.362	3.168	OinIcelh	0.120	0.420	3.484
graphite	0.127	0.533	4.182	OinD2O	0.126	0.471	3.730
graphite-10P	0.125	0.472	3.766	DinD2O	0.131	0.334	2.555
graphite-30P	0.135	0.590	4.382	OinUO2	0.126	0.479	3.805
Be-metal	0.124	0.485	3.898	UinUO2	0.126	0.561	4.608
OinBeO	0.127	0.499	3.930	NinUN	0.120	0.486	4.067
BeinBeO	0.124	0.485	3.917	UinUN	0.122	0.475	4.065
HinH2O	0.132	0.488	3.704	HinYH2	0.151	0.525	3.485
HinCH2	0.127	0.462	3.649	YinYH2	0.117	0.494	4.239
CinSiC	0.123	0.492	3.988	HinZrH	0.125	0.370	2.968
SiinSiC	0.120	0.530	4.397	ZrinZrH	0.116	0.468	4.016

## Current and Future

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- OTF sampling treatment has been applied to 24 materials in the ENDF/B-VIII.0 library.
- A Fortran based sampling paradigm has been developed
- Updating to ENDF/B-VIII.1 when released
- Implementation into MCNP
- Linearization optimization of the OTF treatment



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